



DECAN: Decremental Performance Analysis Tool via Binary Patching

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Optimization process

- Gathering data (ie. code characterization);
- Diagnosing the problem;
- Prescribing a solution.

Tedious process

- Complex modern processors;
- Limited existing methodologies;
- Performance counters not understandable.

Characterization process

- Code analysis to extract code characteristics;
- Applying different types of the code analysis;
- Get different views of the code behavior.

What is DECAN?

- DECAN is a tool for a fine-grained detection of bottlenecks (ie. assembly instruction level);
- DECAN focuses on the hot region of the application;
- DECAN performs on a binary level;
- DECAN uses Pin to patch the binary.

DECAN general concept

1. Measure the original binary;
2. Patch (ie.remove) the memory access instructions in the original binary;
3. New binary is generated for each patch
4. Measure new binaries;
5. Measure are represented in a CSV file.

DECAN: Instruction Removal

- DECAN focuses on SSE memory instructions (loads/stores)
- DECAN replaces the memory instruction by a nop with variable size:

```
movaps (%rsi), %xmm1 -> nop r/m
movaps %xmm1, (%rsi) -> nop r/m
```

- Each patched instruction generates a new binary
- DECAN generates new binaries in 6 different ways: one load, one store, all loads, all stores, all loads/stores, grouping.

How DECAN removes the SSE memory instructions?

Original code

Loop:

```
movsd (%rsi,%rax),%xmm1
mulsd %xmm0,%xmm1
addsd (%rsi,%rax),%xmm1
movsd %xmm1,(%rsi,%rax)
inc %rax
jb Loop
```

One load

- Replace each SSE load with a nop
- Each replacement generates a new binary

One store

- Replace each SSE store with a nop
- Each replacement generates a new binary

All loads

- Replace all SSE loads with nops and generate a new binary

All stores

- Replace all SSE stores with nops and generate a new binary

All loads/stores

- Replace all SSE loads and stores with nops and generate a new binary

Grouping

- Remove (ie.replace by nop) all loads that access to the same base address

RBgauss subroutine

```
DO IDO=1,NREDD
  INC = INDINR(IDO)

  HANB = AM(INC,1)*PHI(INC+1) &
    + AM(INC,2)*PHI(INC-1) &
    + AM(INC,3)*PHI(INC+INPD) &
    + AM(INC,4)*PHI(INC-INPD) &
    + AM(INC,5)*PHI(INC+NIJ) &
    + AM(INC,6)*PHI(INC-NIJ) &
    + SU(INC)

  DLTPHI = UREL*( HANB/AM(INC,7) - PHI(INC) )
  PHI(INC) = PHI(INC) + DLTPHI

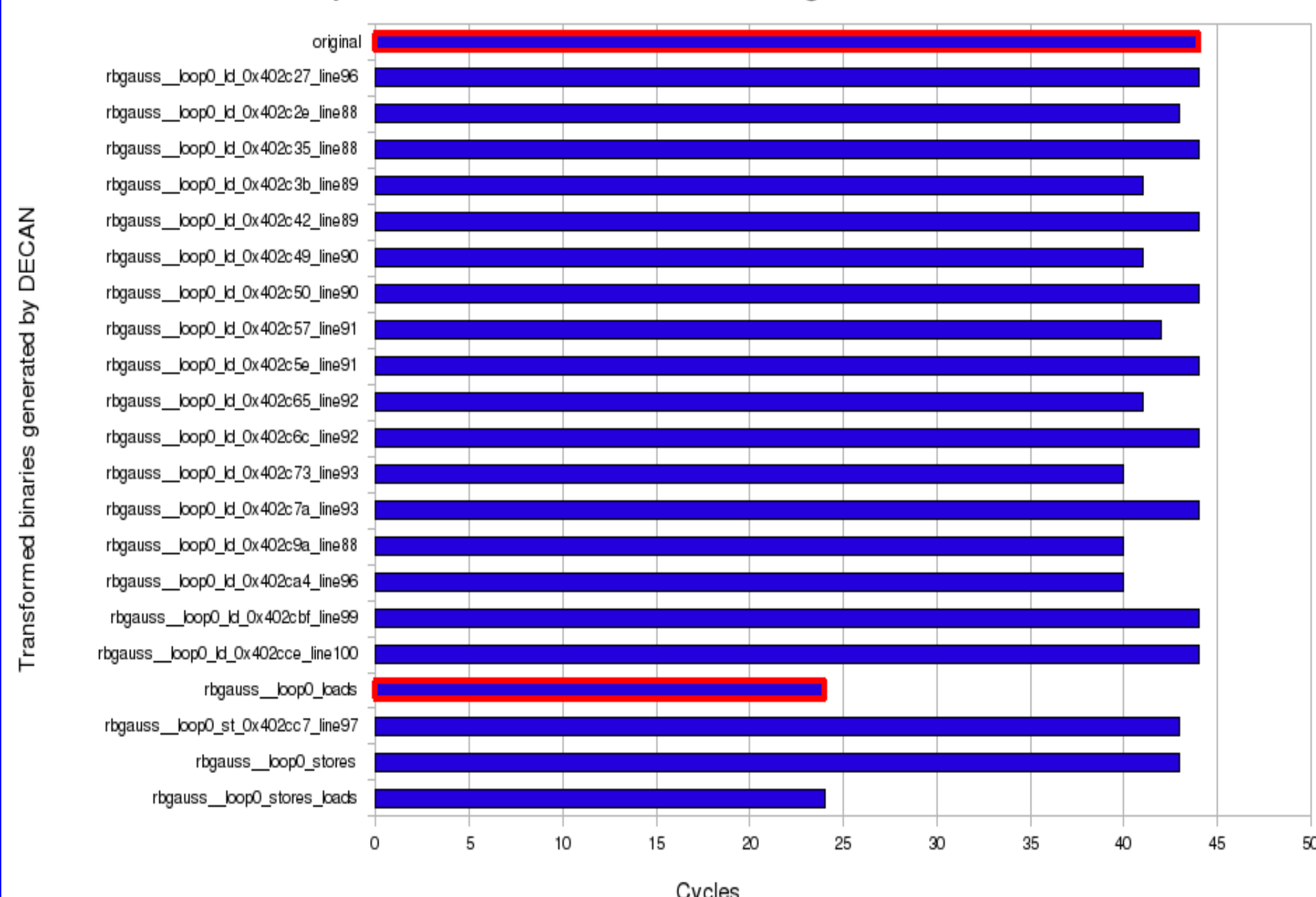
  RESI = RESI + ABS(DLTPHI)
  RSUM = RSUM + ABS(PHI(INC))
ENDDO
```

DECAN application on real-life applications

Matvec subroutine

```
do k=anf3, end3
  do j=anf2, end2
    do i=anf1, end1
      vhilf(i,j,k) = temp(i,j,k) - (
        & (acx(i-1,j,k)*temp(i-1,j,k)
        & (acx(i,j,k)*temp(i+1,j,k)
        & (acy(i,j-1,k)*temp(i,j-1,k)
        & (acy(i,j,k)*temp(i,j+1,k)
        & (acz(i,j,k-1)*temp(i,j,k-1)
        & (acz(i,j,k)*temp(i,j,k+1))
        )/coeffd(i,j,k)
    enddo
  enddo
enddo
```

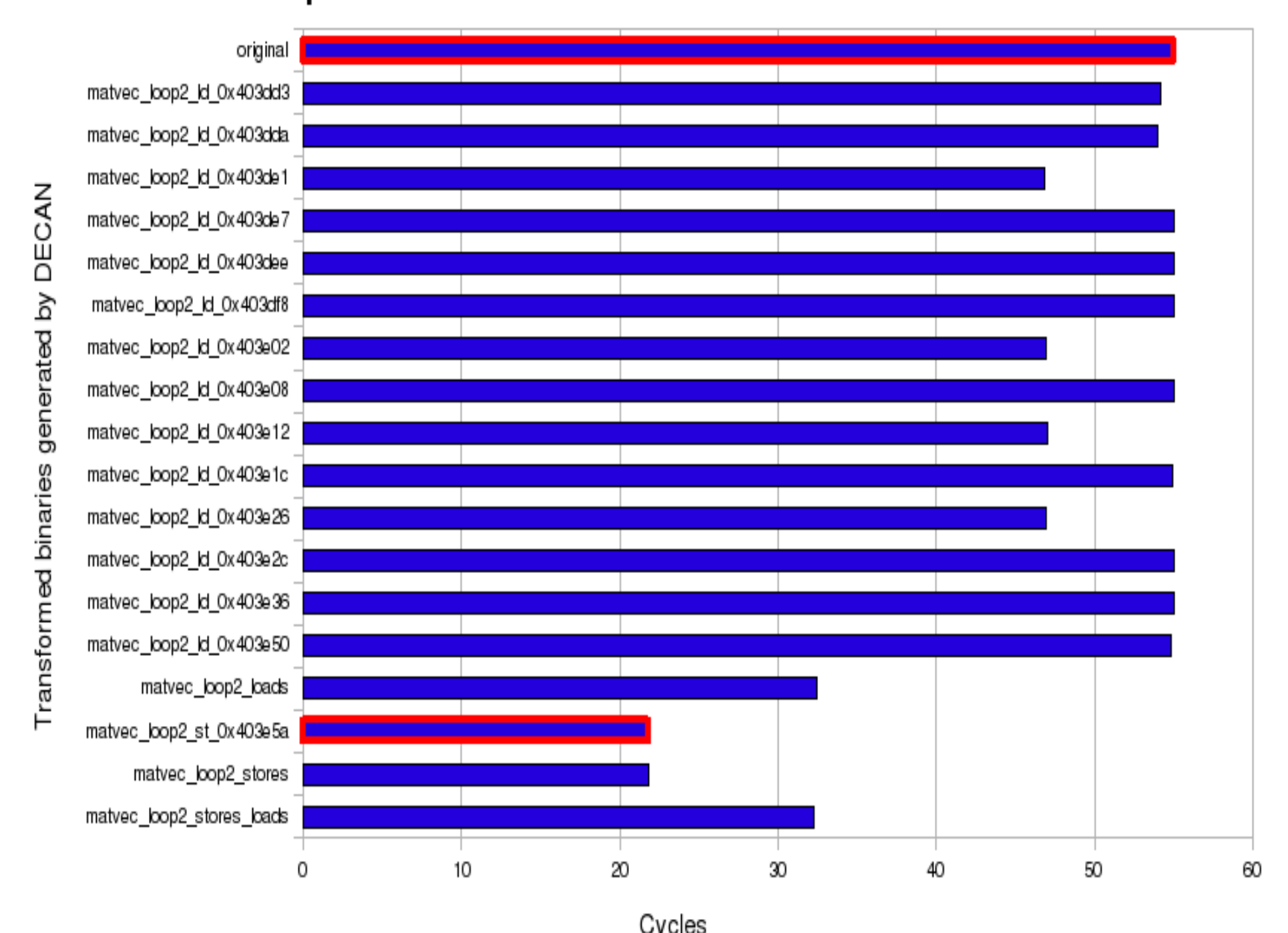
Impact of load/store instructions on RBgauss subroutine



RBgauss subroutine

- Removing all loads improves performance.
 - Removing a set of loads accessing to the same base address (AM array) --> lower bound achieved.
 - The bottleneck is the AM access and only AM.
 - Stride 2 access that causes bottleneck only in AM access.
- > Bottleneck precisely pinpointed, applying an optimization on AM access.

Impact of load/store instructions on Matvec subroutine



Matvec subroutine

- Removing one store improves the performance.
- The store is the bottleneck.
- The store corresponds to the store of vhilf.
- There is a conflict between the store of vhilf and some loads (acx & temp).
- It is a problem of 4K-aliasing: vhilf, acx, and temp have the same address modulo 4K.
- DECAN detects precisely that the bottleneck is the store instruction.

Futur work

- Test DECAN on more applications (SPEC 2006).
- Improve user's feedback: synthesis of DECAN's results.
- Extend DECAN to address branch instructions to detect miss-prediction.

Recom application - Grouping of SSE memory instructions that access to the same base address (AM array)

